## Notice of References Cited Application/Control No. 10/720,928 Applicant(s)/Patent Under Reexamination BUSHNELL ET AL. Examiner Huy Q. Phan Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0025047	02-2004	Mayne et al.	713/200
*	В	US-5,890,055 A	03-1999	Chu et al.	455/16
*	С	US-2003/0139180 A1	07-2003	McIntosh et al.	455/426
*	D	US-2004/0009749 A1	01-2004	Arazi et al.	455/41.2
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			1
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2406015 A	03-2005	United Kingdom	DOCHERTY et al.	H04M 01/60
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	W						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.